



CTS600, CTS601, CTS611

SDIP-6 10Mbit/s High Speed Logic Gate Optocoupler

Features

- High speed 10MBit/s
- High isolation voltage between input and output ($V_{ISO}=5000 V_{RMS}$)
- Guaranteed performance from -40°C to 85°C
- Operating Temperature range of -55°C to 100°C
- Wide operating voltage range of 3.3V to 5.5V
- RoHS and REACH Compliance
- MSL class 1
- Regulatory Approvals
 - ✓ UL - UL1577 (E364000)
 - ✓ VDE - EN60747-5-5(VDE0884-5)
 - ✓ CQC – GB4943.1, GB8898(14001104999)
 - ✓ IEC62368 (FI/41119)

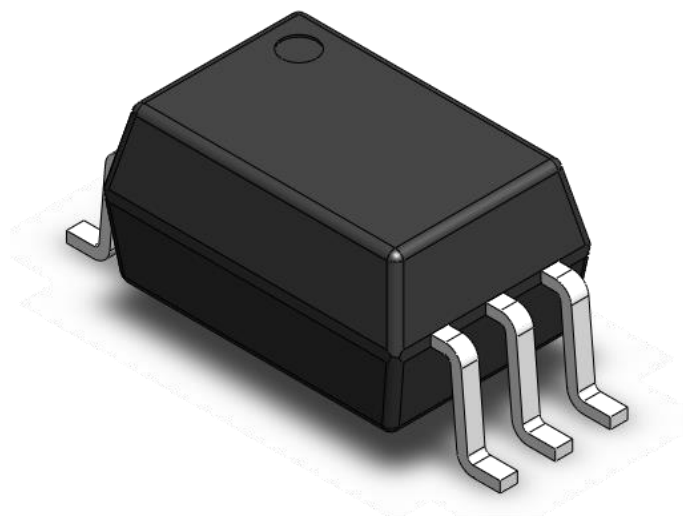
Description

The CTS600, CTS601, and CTS611 optocouplers consist of an AlGaAs LED, optically coupled to a very high speed integrated photo-detector logic gate with a strobe able output. The output of the detect IC is a high speed logic gate integrated with a photo detector. A maximum input signal of 5mA will provide a minimum output sink current of 13mA.

Applications

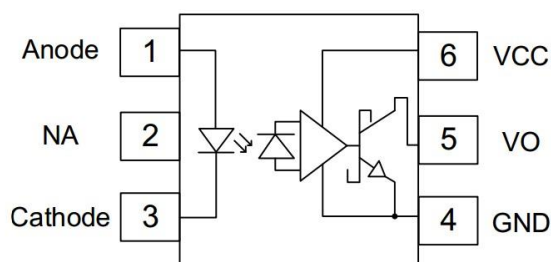
- Line receivers
- Telecommunication equipment
- High speed logic ground isolation
- Feedback loop in switch-mode power supplies
- Home appliances

Package Outline



Note: Different bending options available. See package dimension.

Schematic



Truth Table

Input	Output
L	H
H	L



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Absolute Maximum Ratings $T_A = 25^\circ\text{C}$, unless otherwise specified

Stresses in excess of the absolute maximum ratings can cause permanent damage to the device. Functional operation of the device is not implied at these or any other conditions in excess of those given in the operational sections of this document. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameters	Ratings	Units	Notes
V _{ISO}	Isolation voltage (AC, 1 minute, 40 ~ 60% R.H.)	5000	V _{RMS}	
T _{OPR}	Operating temperature	-55 ~ +100	°C	
T _{STG}	Storage temperature	-55 ~ +125	°C	
T _{SOL}	Soldering temperature (For 10 seconds)	260	°C	
Emitter				
I _F	Forward current	50	mA	
V _R	Reverse voltage	5	V	
P _I	Power dissipation	100	mW	
Detector				
P _O	Power dissipation	85	mW	
I _O	Average Output current	50	mA	
V _O	Output voltage	3.0 ~ 7.0	V	1min(Max.)
V _{CC}	Supply voltage	3.0 ~ 7.0	V	
V _E	Enable Input Voltage Not to Exceed VCC by more than 500mV	5.5	V	



Electrical Characteristics $T_A = -40 - 85^\circ\text{C}$ (unless otherwise specified). Typical values are measured at $T_A = 25^\circ\text{C}$ and $V_{CC}=5\text{V}$

Emitter Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
V_F	Forward voltage	$I_F = 10\text{mA}$	-	1.4	1.6	V	
V_R	Reverse Voltage	$I_R = 5\mu\text{A}$	5.0	-	-	V	
$\Delta V_F/\Delta T_A$	Temperature coefficient of forward voltage	$I_F = 10\text{mA}$	-	-1.6	-	mV/°C	

Detector Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
I_{CCH}	Logic High Supply Current	$I_F=0\text{mA}, V_{CC}=3.3\text{V}$	-	4.0	10	mA	
		$I_F=0\text{mA}, V_{CC}=5.5\text{V}$	-	6.5	10		
I_{CCL}	Logic Low Supply Current	$I_F=10\text{mA}, V_{CC}=3.3\text{V}$	-	5.5	13	mA	
		$I_F=10\text{mA}, V_{CC}=5.5\text{V}$	-	8.8	13		

Transfer Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
I_{FT}	Input Threshold Current	$V_{CC}=3.3\text{V}, V_O=0.6\text{V}, I_O=13\text{mA}$	-	1.6	5	mA	
		$V_{CC}=5.5\text{V}, V_O=0.6\text{V}, I_O=13\text{mA}$	-	2.5	5		
I_{OH}	Logic High Output Current	$I_F=250\mu\text{A}, V_O=V_{CC}=3.3\text{V}$	-	7.0	100	μA	
		$I_F=250\mu\text{A}, V_O=V_{CC}=5.5\text{V}$	-	2.0	100		
V_{OL}	Low Level Output Voltage	$I_F=5\text{mA}, V_{CC}=3.3\text{V}, I_O=13\text{mA}$	-	0.45	0.6	V	
		$I_F=5\text{mA}, V_{CC}=5.5\text{V}, I_O=13\text{mA}$	-	0.35	0.6		



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Electrical Characteristics $T_A = -40 - 85^\circ\text{C}$ (unless otherwise specified). Typical values are measured at $T_A = 25^\circ\text{C}$, $V_{CC} = 5\text{V}$ and $I_F = 7.5\text{mA}$

Switching Characteristics

Symbol	Parameters		Test Conditions	Min	Typ	Max	Units	Notes
T_{PHL}	Propagation Delay Time Logic High to Logic Low		$C_L = 15\text{pF}, R_L = 350\Omega$	-	34	75	ns	
T_{PLH}	Propagation Delay Time Logic Low to Logic High			-	39	75	ns	
T_r	Output Rise Time			-	37	-	ns	
T_f	Output Fall Time			-	10	-	ns	
CM_H	Common Mode Transient Immunity at Logic High	CTS600	$I_F = 0\text{mA}, V_{OH} = 2.0\text{V}, R_L = 350\Omega, T_A = 25^\circ\text{C}, V_{CM} = 10\text{Vp-p}$	-	-	-	V/ μs	
		CTS601	$I_F = 0\text{mA}, V_{OH} = 2.0\text{V}, R_L = 350\Omega, T_A = 25^\circ\text{C}, V_{CM} = 50\text{Vp-p}$	5000	-	-		
		CTS611	$I_F = 0\text{mA}, V_{OH} = 2.0\text{V}, R_L = 350\Omega, T_A = 25^\circ\text{C}, V_{CM} = 1000\text{Vp-p}$	20000	-	-		
CM_L	Common Mode Transient Immunity at Logic Low	CTS600	$I_F = 7.5\text{mA}, V_{OL} = 0.8\text{V}, R_L = 350\Omega, T_A = 25^\circ\text{C}, V_{CM} = 10\text{Vp-p}$	-	-	-	V/ μs	
		CTS601	$I_F = 7.5\text{mA}, V_{OL} = 0.8\text{V}, R_L = 350\Omega, T_A = 25^\circ\text{C}, V_{CM} = 50\text{Vp-p}$	5000	-	-		
		CTS611	$I_F = 7.5\text{mA}, V_{OL} = 0.8\text{V}, R_L = 350\Omega, T_A = 25^\circ\text{C}, V_{CM} = 1000\text{Vp-p}$	20000	-	-		



Typical Characteristic Curves $T_A = 25^\circ\text{C}$, unless otherwise specified

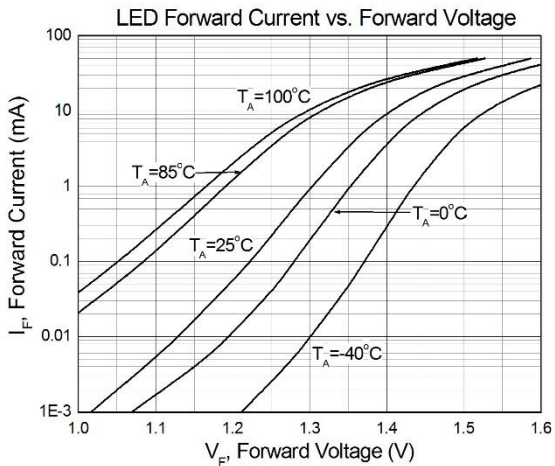


Figure 1

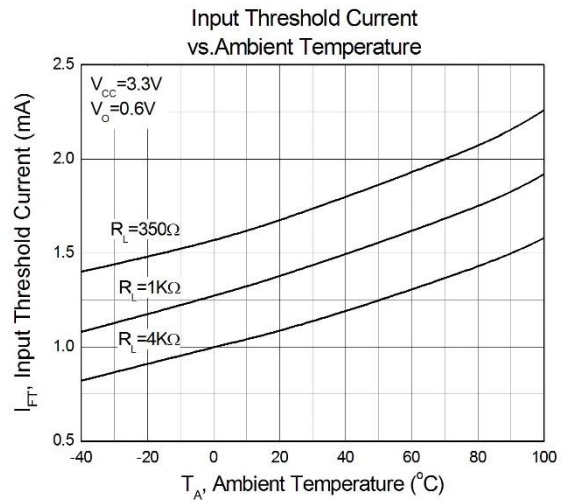


Figure 2

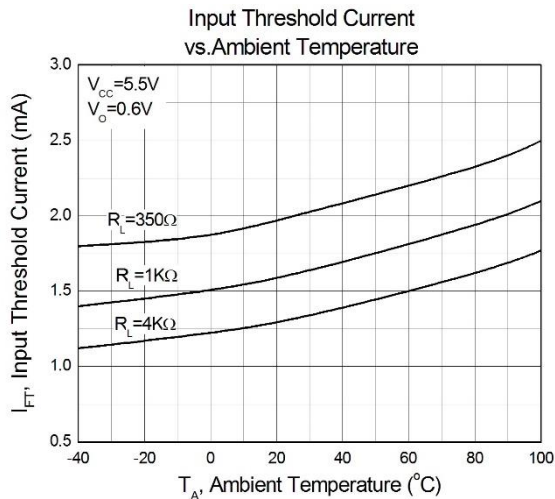


Figure 3

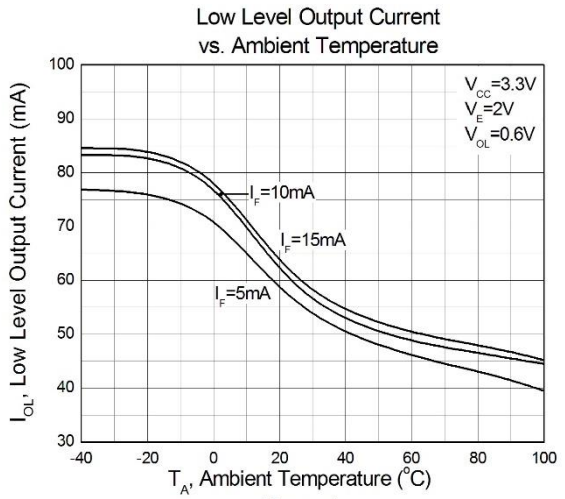


Figure 4

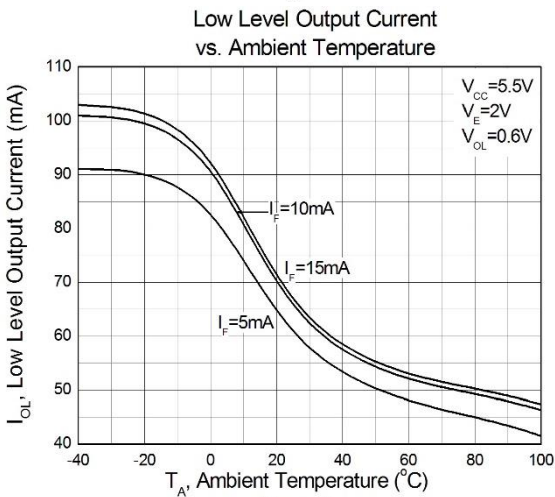


Figure 5

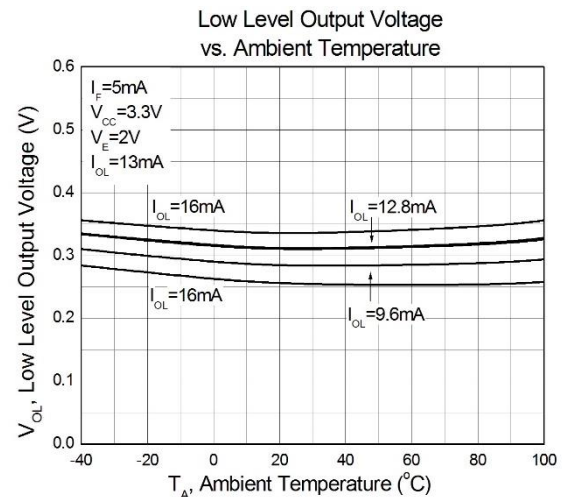


Figure 6



Typical Characteristic Curves $T_A = 25^\circ\text{C}$, unless otherwise specified

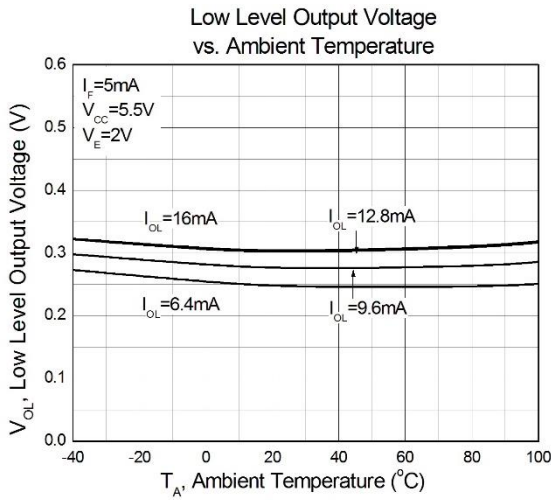


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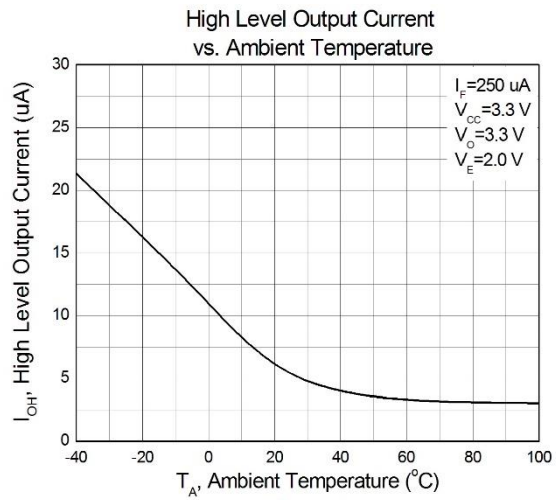


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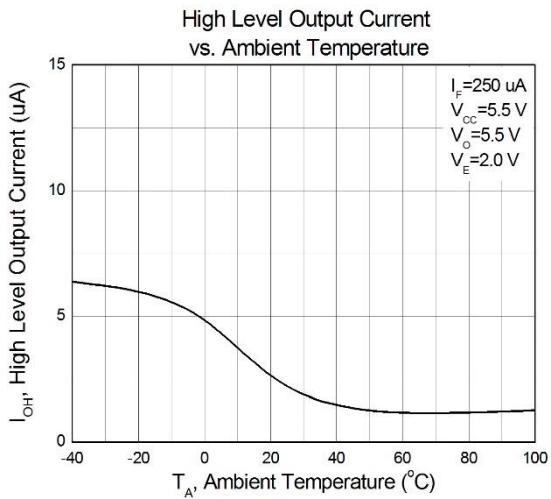


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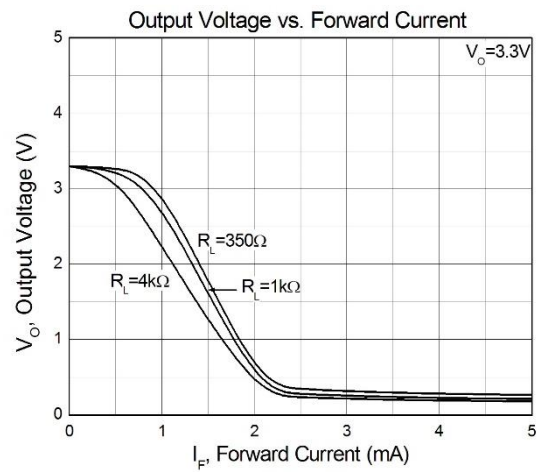


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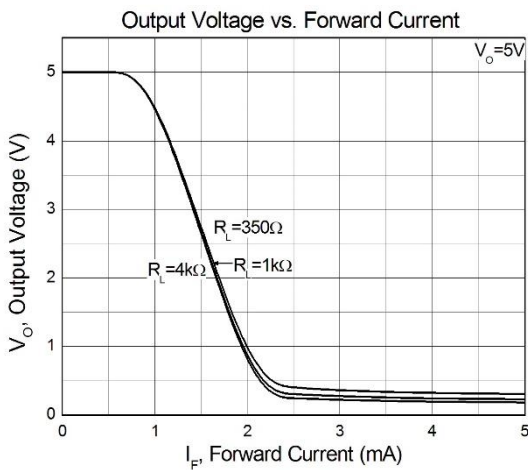


Figure 11

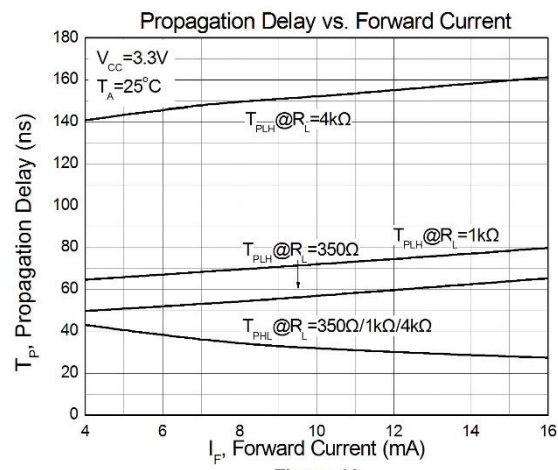


Figure 12



Typical Characteristic Curves $T_A = 25^\circ\text{C}$, unless otherwise specified

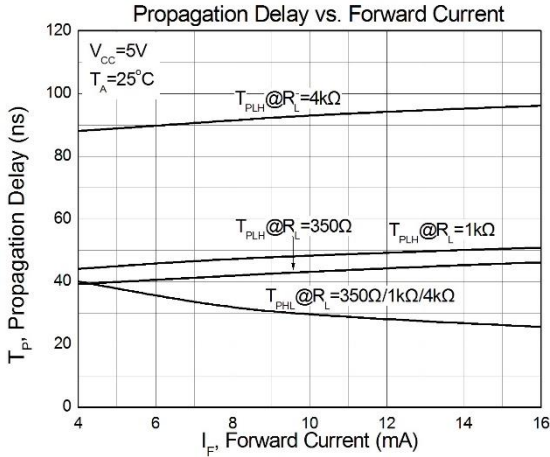


Figure 13

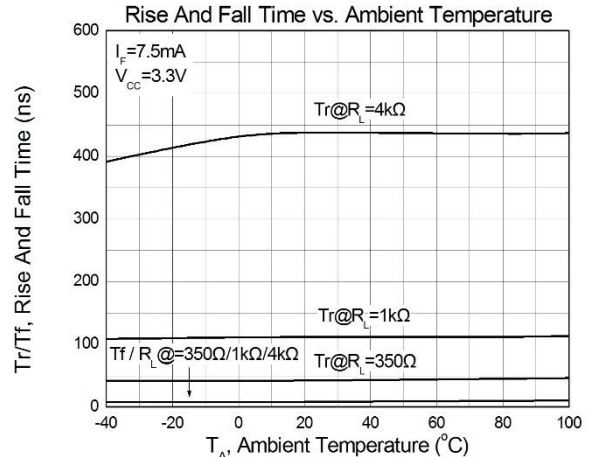


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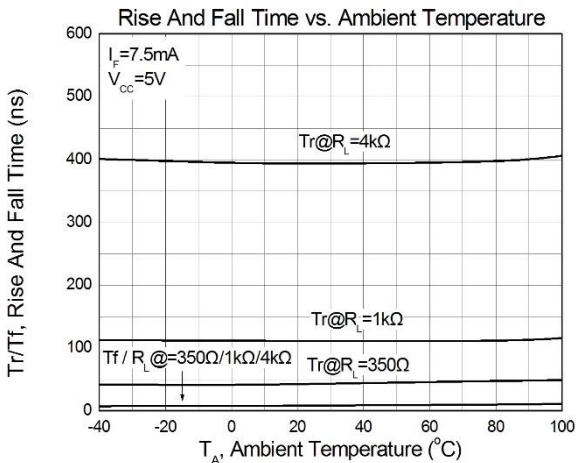


Figure 15

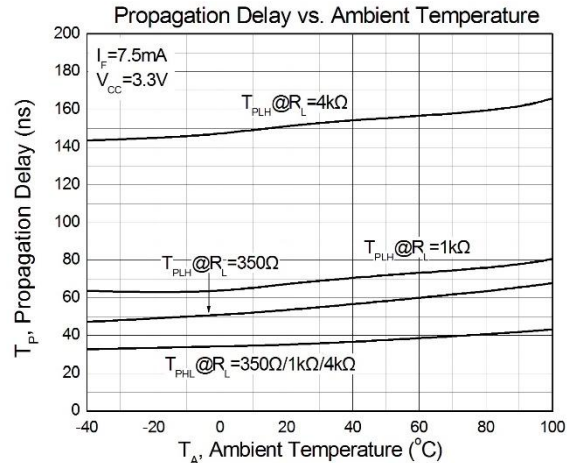


Figure 16

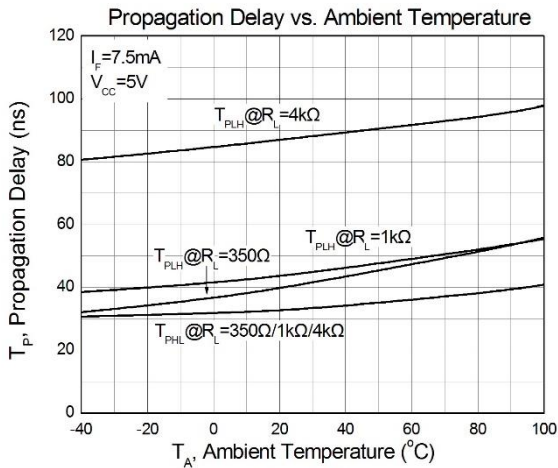


Figure 17

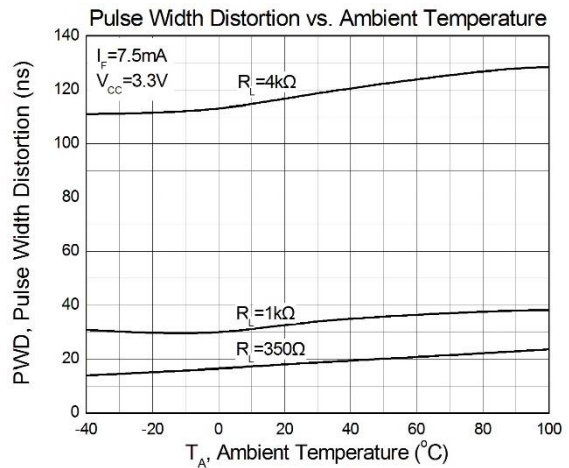


Figure 18



Typical Characteristic Curves $T_A = 25^\circ\text{C}$, unless otherwise specified

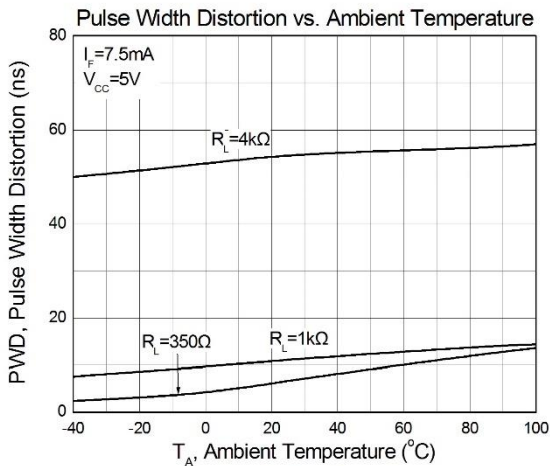


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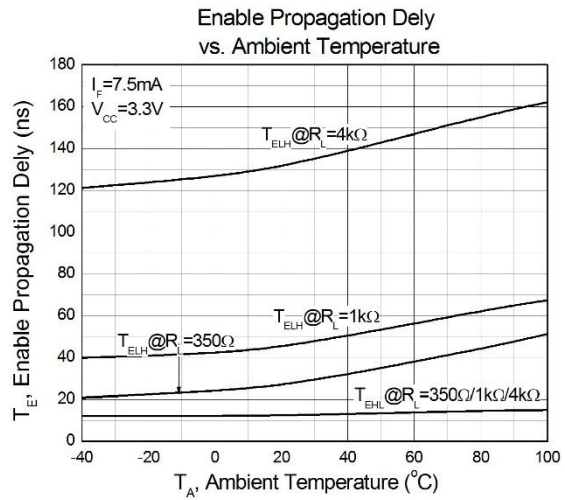


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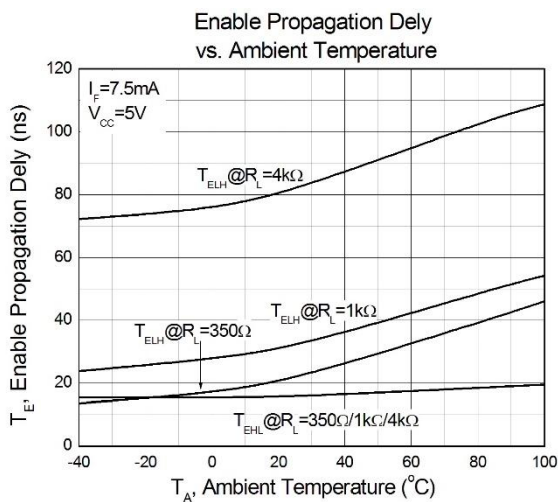


Figure 21



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Test Circuits

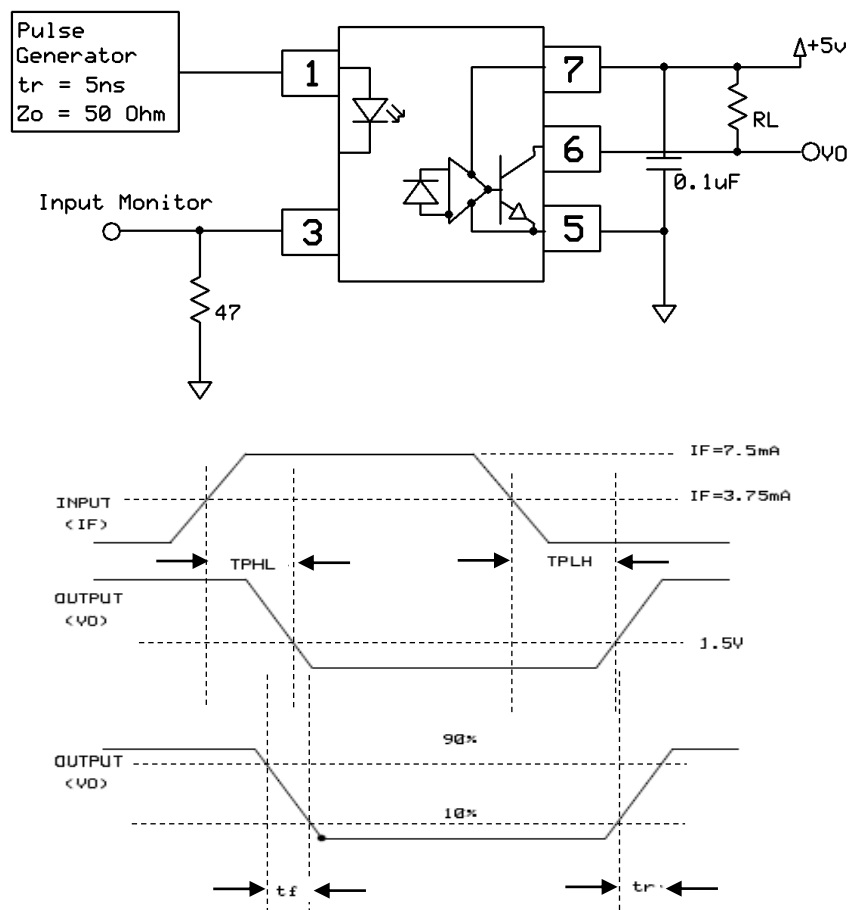


Figure 22: Switching Time Test Circuit



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Test Circuits

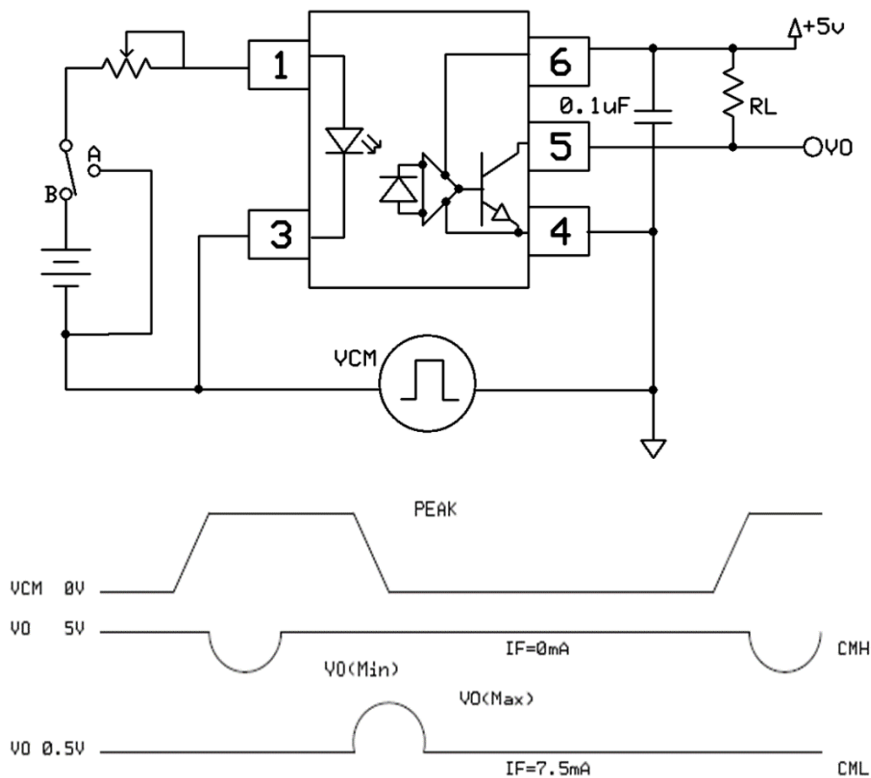


Figure 23: CMR Test Circuit

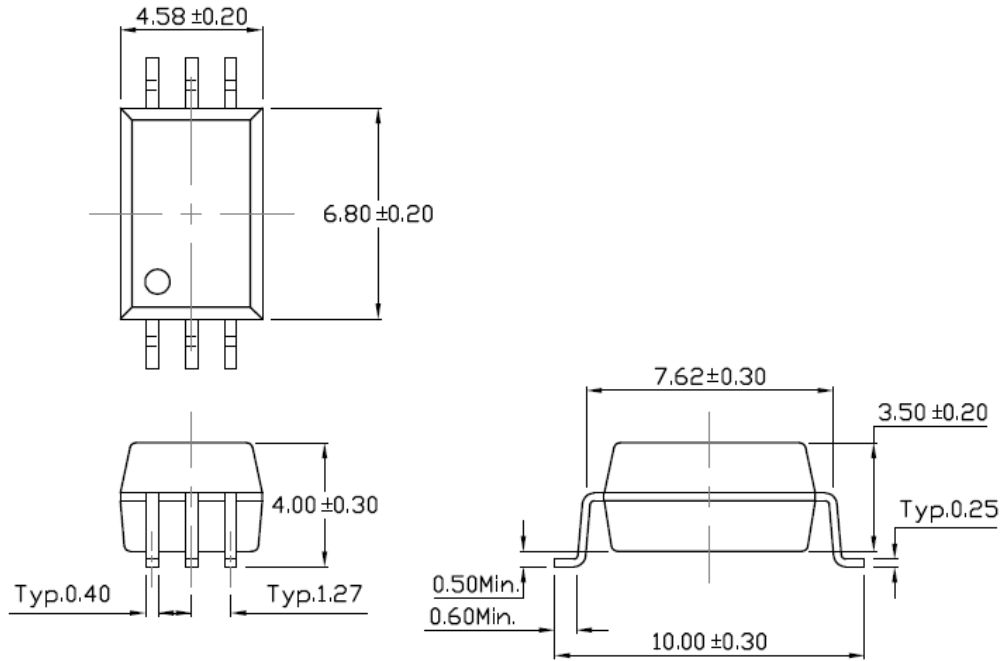


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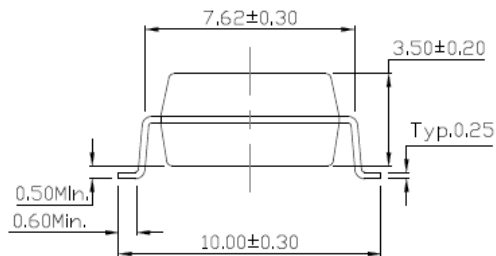
Package Dimension *Dimensions in mm unless otherwise stated*

Surface Mount Lead Forming

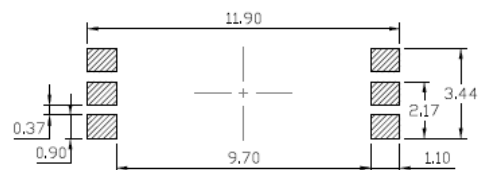
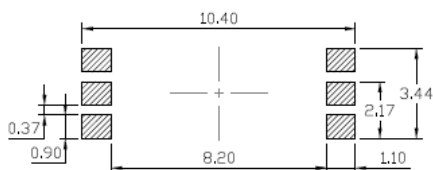
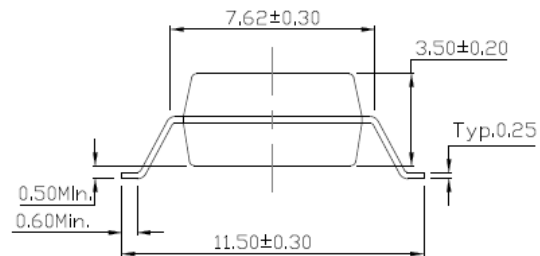


Forming Option *Dimensions in mm unless otherwise stated*

S Type



SM Type

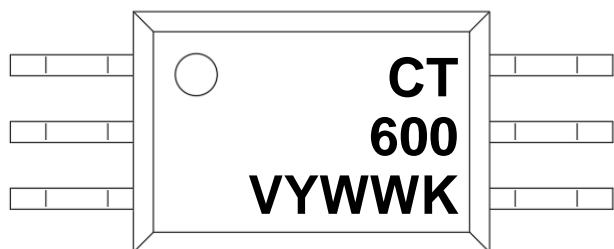




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Marking Information



Note:

- CT : Denotes "CT Micro"
- 600 : Part Number(600,601,611)
- V : VDE Safety Mark Option (Blank or V)
- Y : One Digit Year Code
- WW : Two Digit Work Week
- K : Manufacturing Code

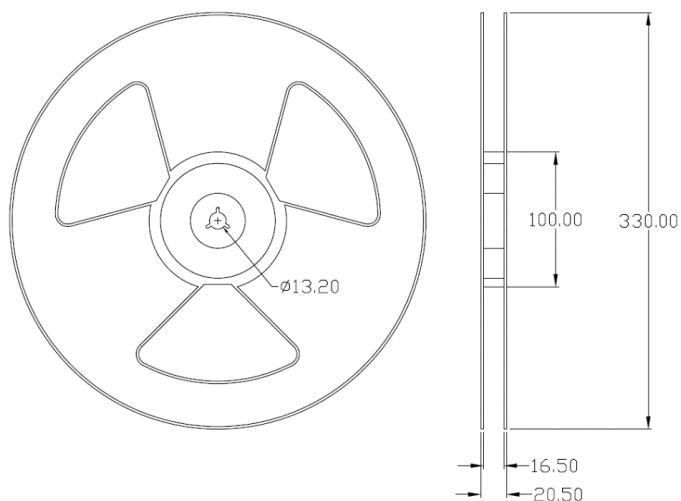
Ordering Information

CTS6XX(V)(Y)(Z)

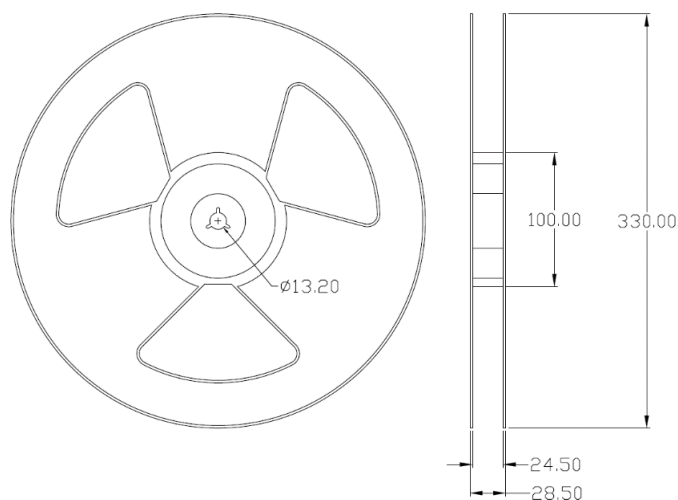
- CT = Denotes "CT Micro"
- X = Part Number(00, 01, 11)
- V = VDE Safety Mark Option (Blank or V)
- Y = Lead Form Option (Blank, M)
- Z = Tape and Reel Option (T1, T2)

Reel Dimension *All dimensions are in mm, unless otherwise stated*

Option S(T1/T2)



Option SM(T1/T2)





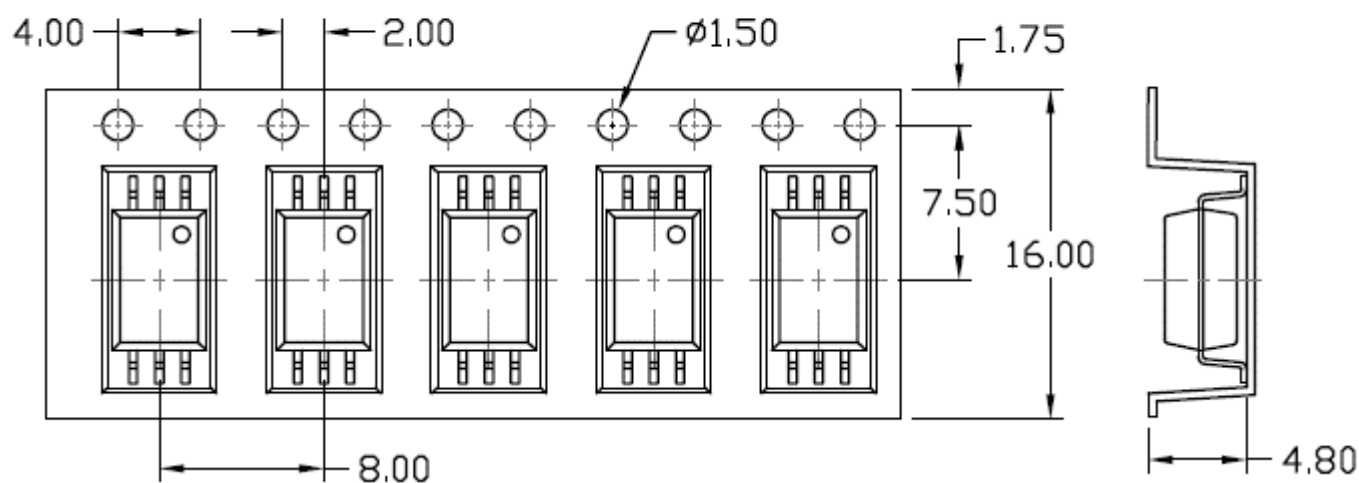
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Carrier Tape Specifications *Dimensions in mm unless otherwise stated*

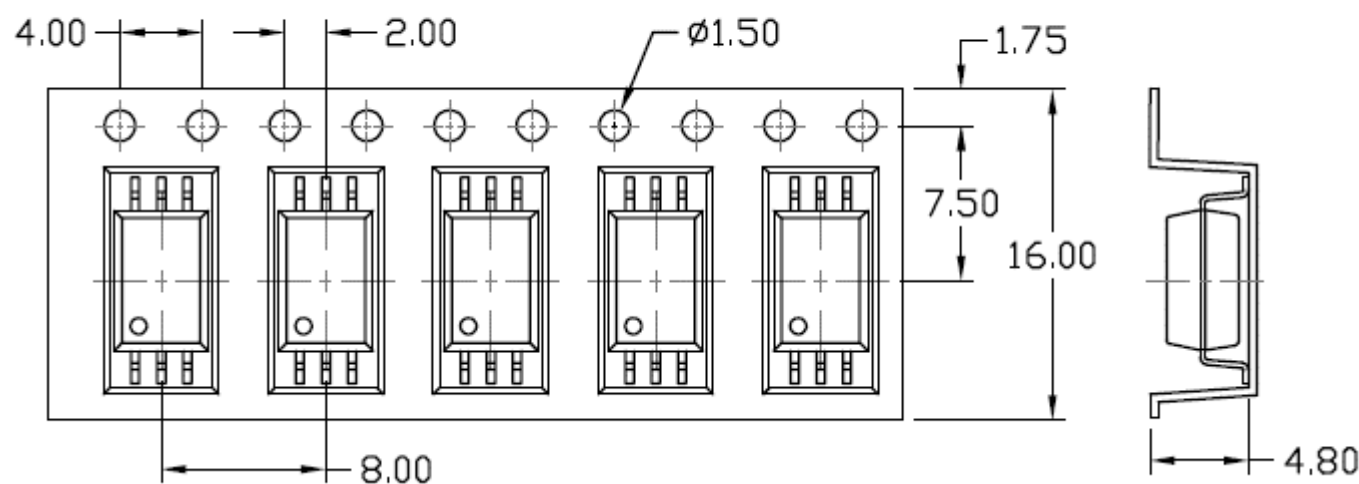
Option S(T1)

Input Direction
→



Option S(T2)

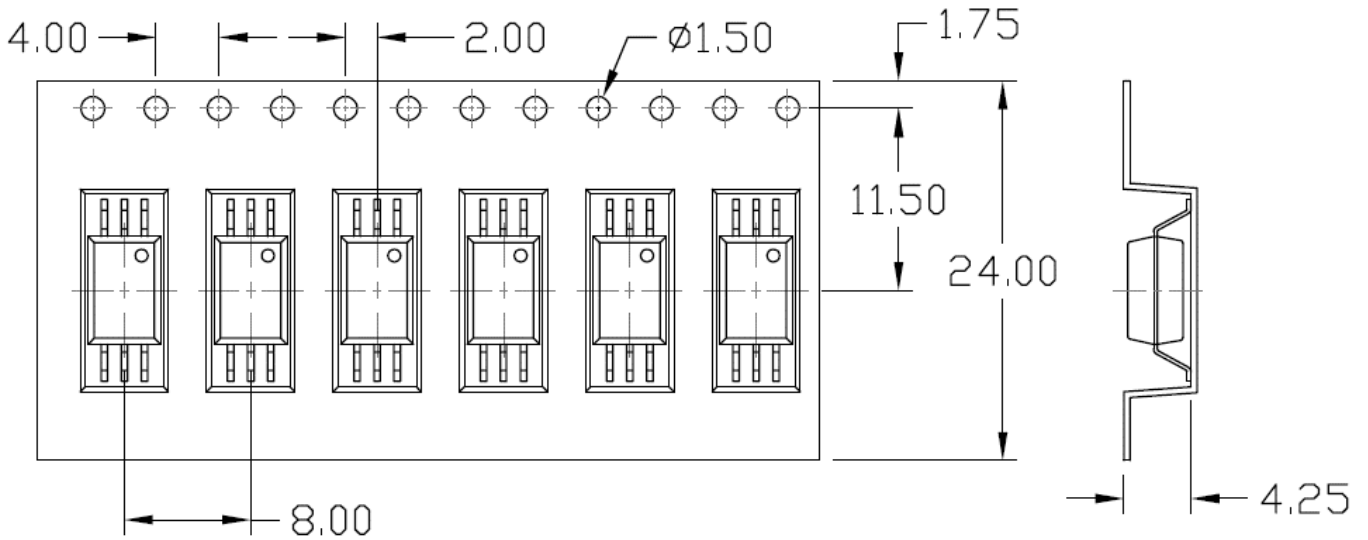
Input Direction
→





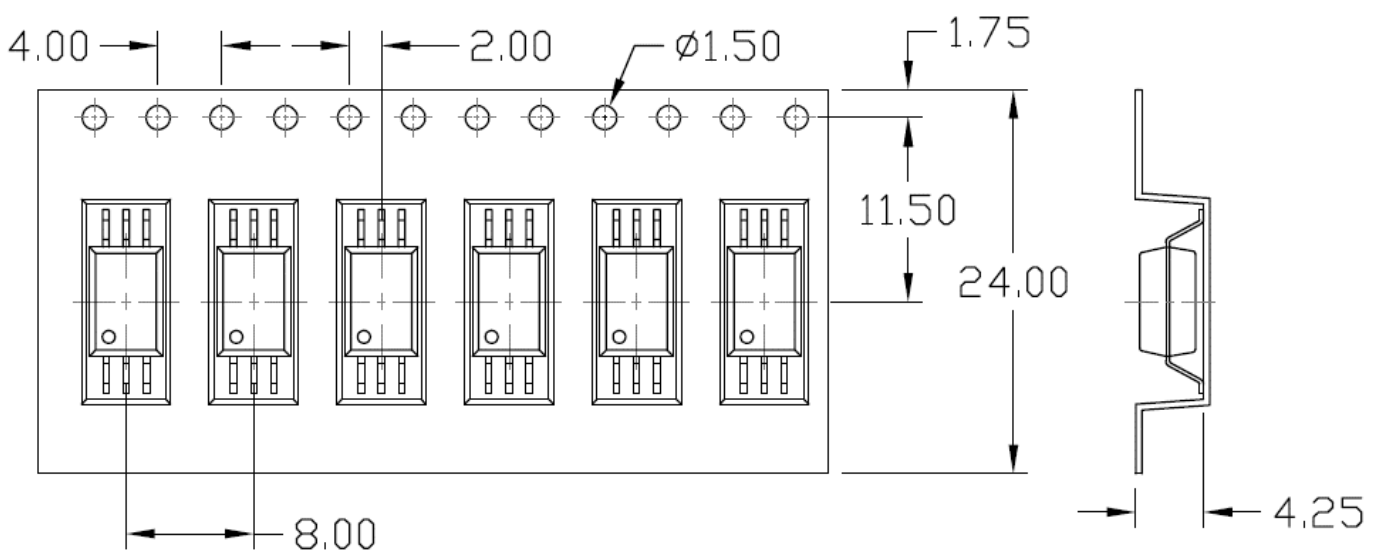
Option SM (T1)

Input Direction



Option SM (T2)

Input Direction





Solderability spec (Follow the JEDEC standard JESD22-B102)

Reflow Soldering: Immersed surface, other than the end of pin as cut-surface, must be covered by solder.

Solder-Bath: More than 95% of the electrode must be covered with solder.

Wave soldering (Follow the JEDEC standard JESD22-A111)

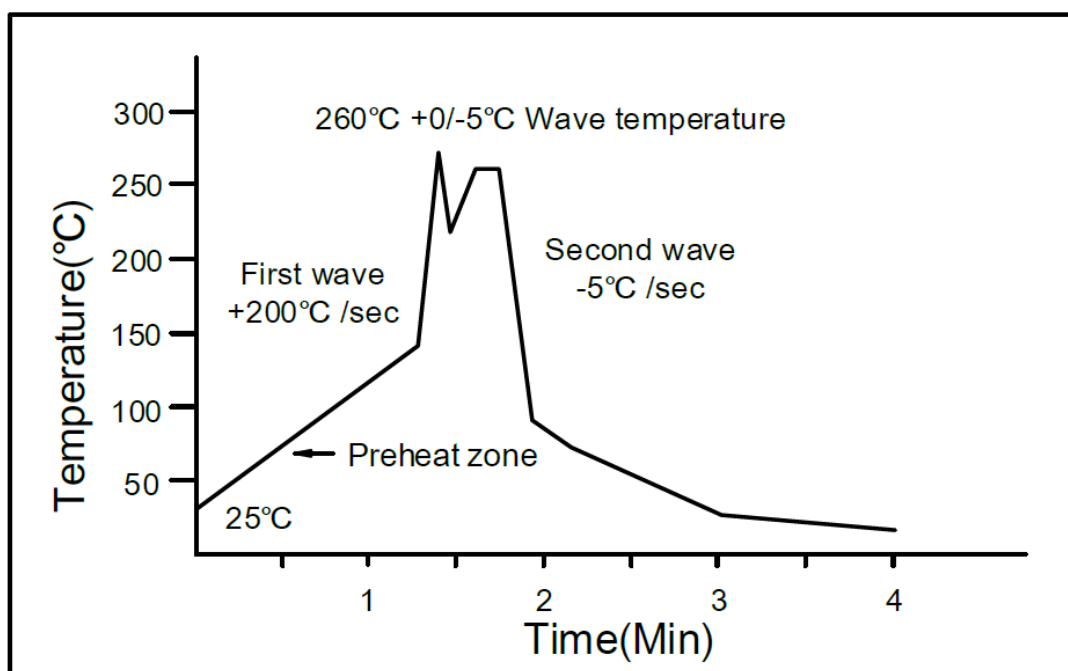
One time soldering is recommended within the condition of temperature.

Temperature: $260 \pm 0/-5^\circ\text{C}$.

Time: 10 sec.

Preheat temperature: 25 to 140°C .

Preheat time: 30 to 80 sec.



Iron soldering (Follow the standard MIL-STD 202G, Method 210F)

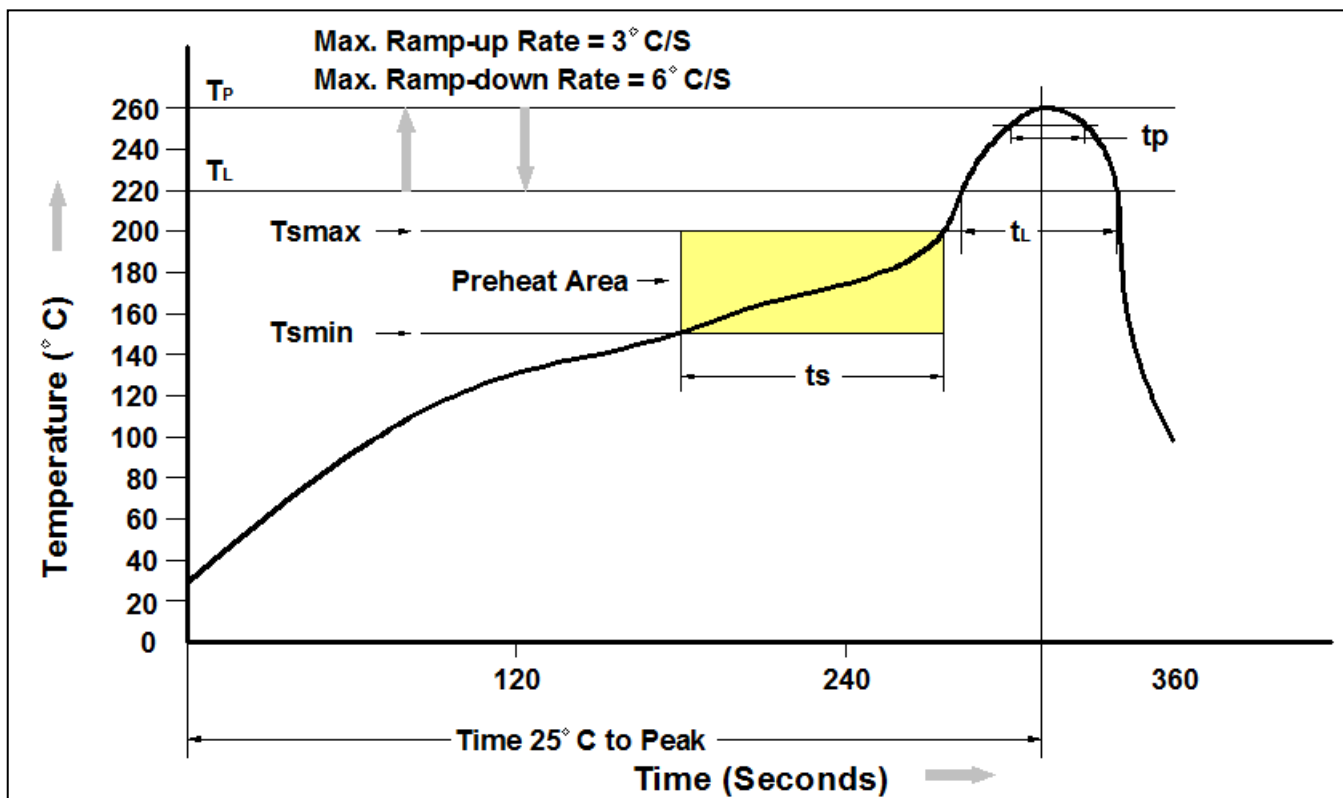
Allow single lead soldering in every single process.

One time soldering is recommended. Temperature: $350 \pm 10^\circ\text{C}$

Time: 5 sec max.



Reflow Profile (Follow the JEDEC standard J-STD-020)



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T_{smin})	150°C
Temperature Max. (T_{smax})	200°C
Time (t_s) from (T_{smin} to T_{smax})	60-120 seconds
Ramp-up Rate (t_L to t_P)	3°C/second max.
Liquidous Temperature (T_L)	217°C
Time (t_L) Maintained Above (T_L)	60 – 150 seconds
Peak Body Package Temperature	260°C +0°C / -5°C
Time (t_P) within 5°C of 260°C	30 seconds
Ramp-down Rate (T_P to T_L)	6°C/second max
Time 25°C to Peak Temperature	8 minutes max.



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- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.*